



PATENT
Customer No. 22,852
Attorney Docket No. 3180.0269-00

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Chie IWASA

Application No.: 09/708,490

Filed: November 9, 2000

For: SEMICONDUCTOR TESTING
METHOD AND SEMICONDUCTOR
TESTING APPARATUS FOR
SEMICONDUCTOR DEVICES, AND
PROGRAM FOR EXECUTING
SEMICONDUCTOR TESTING
METHOD

Group Art Unit: 2863

Examiner: Lau, Tung S.

Commissioner for Patents
Washington, DC 20231

Sir:

AMENDMENT

In reply to the Office Action dated April 18, 2003, please amend the application
as follows:

IN THE CLAIMS:

Please amend claims 1-3, 5-7, 9-11, and 13-19 as follows:

1. (Twice Amended) A semiconductor testing apparatus for testing semiconductor devices, configured to feed back data of returned samples which have been shipped as good samples, but returned from a user to a manufacture as faulty

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